



# M27V512

## 512 Kbit (64Kb x 8) Low Voltage UV EPROM and OTP EPROM

NOT FOR NEW DESIGN

- **M27V512 is replaced by the M27W512**
- **3V to 3.6V LOW VOLTAGE** in READ OPERATION
- **ACCESS TIME:** 100ns
- **LOW POWER CONSUMPTION:**
  - Active Current 10mA at 5MHz
  - Standby Current 10 $\mu$ A
- **PROGRAMMING VOLTAGE:** 12.75V  $\pm$  0.25V
- **PROGRAMMING TIME:** 100 $\mu$ s/word
- **ELECTRONIC SIGNATURE**
  - Manufacturer Code: 20h
  - Device Code: 3Dh

### DESCRIPTION

The M27V512 is a low voltage 512 Kbit EPROM offered in the two ranges UV (ultra violet erase) and OTP (one time programmable). It is ideally suited for microprocessor systems and is organized as 65,536 by 8 bits.

The M27V512 operates in the read mode with a supply voltage as low as 3V. The decrease in operating power allows either a reduction of the size of the battery or an increase in the time between battery recharges.

The FDIP28W (window ceramic frit-seal package) has transparent lid which allows the user to expose the chip to ultraviolet light to erase the bit pattern. A new pattern can then be written to the device by following the programming procedure.

For applications where the content is programmed only one time and erasure is not required, the M27V512 is offered in PDIP28, PLCC32 and TSOP28 (8 x 13.4 mm) packages.

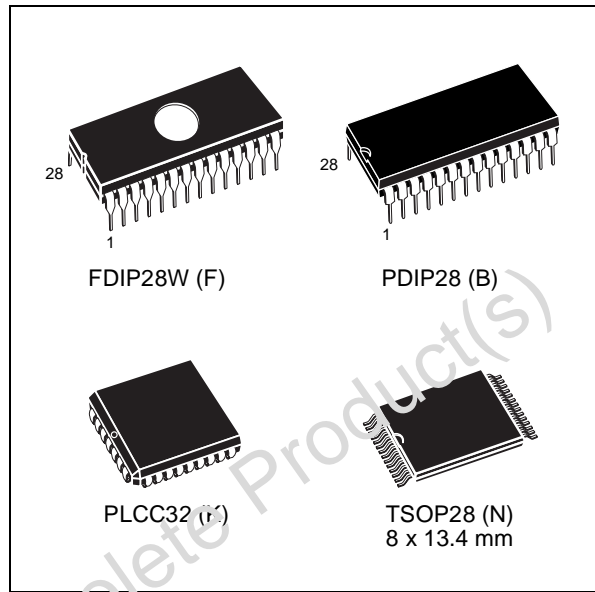
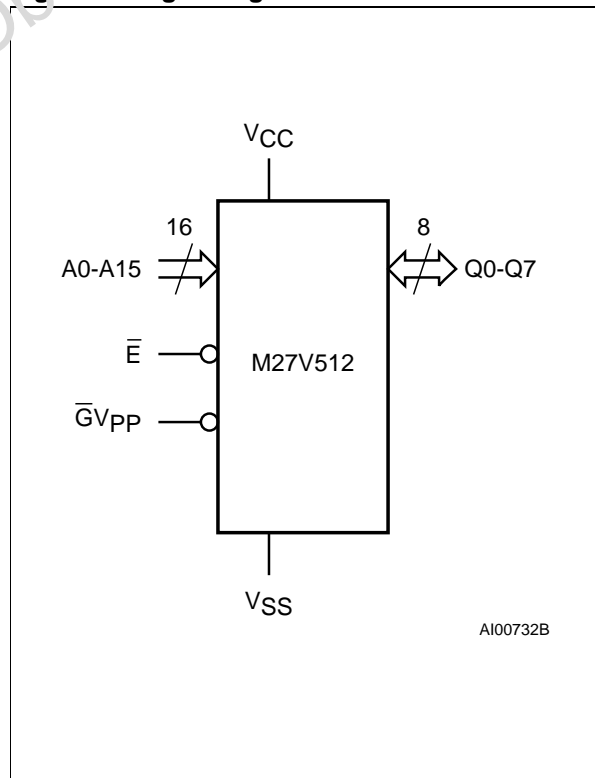
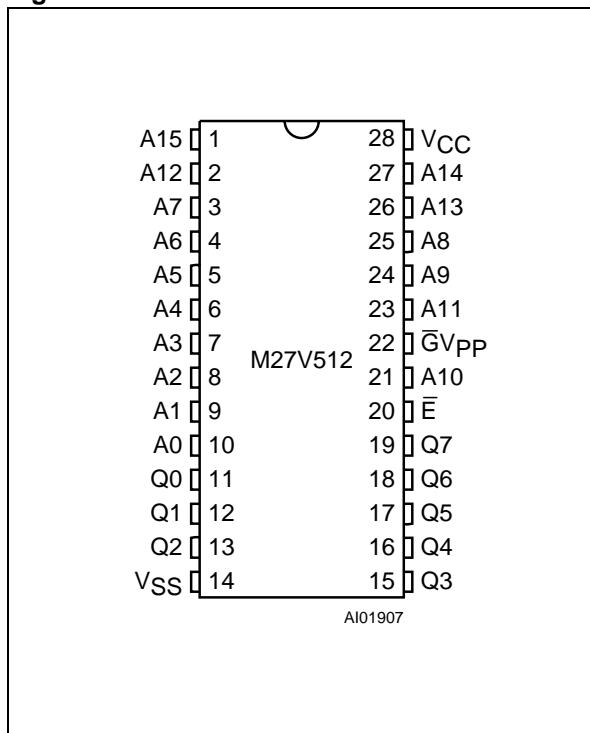


Figure 1. Logic Diagram

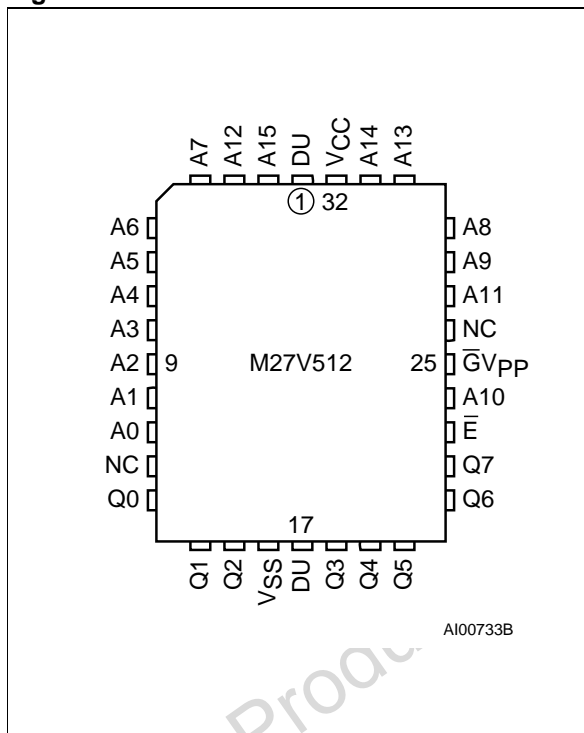


# M27V512

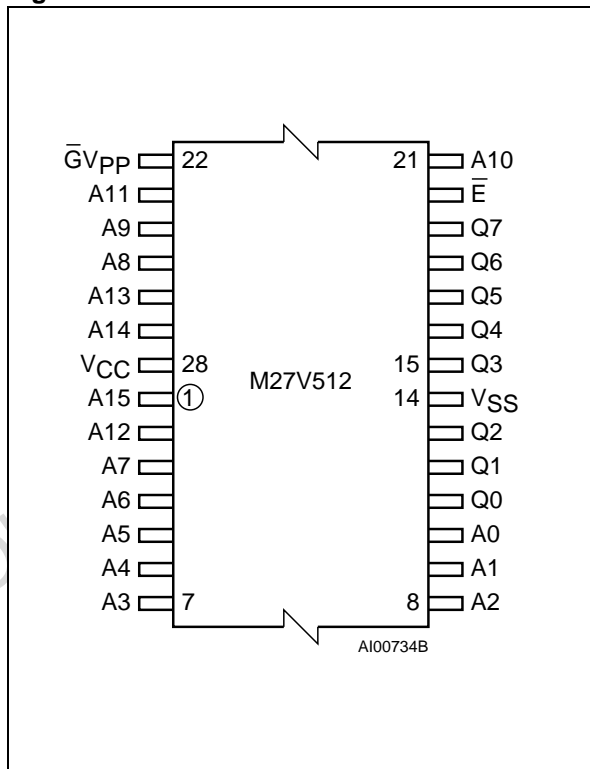
**Figure 2A. DIP Connections**



**Figure 2B. LCC Connections**



**Figure 2C. TSOP Connections**



**Table 1. Signal Names**

A0-A15	Address Inputs
Q0-Q7	Data Outputs
$\bar{E}$	Chip Enable
$\bar{GVP}$	Output Enable
VCC	Supply Voltage
VSS	Ground
NC	Not Connected Internally
DU	Don't Use

**Table 2. Absolute Maximum Ratings** <sup>(1)</sup>

Symbol	Parameter	Value	Unit
T <sub>A</sub>	Ambient Operating Temperature <sup>(3)</sup>	-40 to 125	°C
T <sub>BIAS</sub>	Temperature Under Bias	-50 to 125	°C
T <sub>STG</sub>	Storage Temperature	-65 to 150	°C
V <sub>IO</sub> <sup>(2)</sup>	Input or Output Voltage (except A9)	-2 to 7	V
V <sub>CC</sub>	Supply Voltage	-2 to 7	V
V <sub>A9</sub> <sup>(2)</sup>	A9 Voltage	-2 to 13.5	V
V <sub>PP</sub>	Program Supply Voltage	-2 to 14	V

Note: 1. Except for the rating "Operating Temperature Range", stresses above those listed in the Table "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

2. Minimum DC voltage on Input or Output is -0.5V with possible undershoot to -2.0V for a period less than 20ns. Maximum DC voltage on Output is V<sub>CC</sub> +0.5V with possible overshoot to V<sub>CC</sub> +2V for a period less than 20ns.
3. Depends on range.

**Table 3. Operating Modes**

Mode	$\bar{E}$	$\bar{GV}_{PP}$	A9	Q7-Q0
Read	V <sub>IL</sub>	V <sub>IL</sub>	X	Data Out
Output Disable	V <sub>IL</sub>	V <sub>IH</sub>	X	Hi-Z
Program	V <sub>IL</sub> Pulse	V <sub>PP</sub>	X	Data In
Program Inhibit	V <sub>IH</sub>	V <sub>PP</sub>	X	Hi-Z
Standby	V <sub>IH</sub>	X	X	Hi-Z
Electronic Signature	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>ID</sub>	Codes

Note: X = V<sub>IH</sub> or V<sub>IL</sub>, V<sub>ID</sub> = 12V ± 0.5V.

**Table 4. Electronic Signature**

Identifier	A0	Q7	Q6	Q5	Q4	Q3	Q2	Q1	Q0	Hex Data
Manufacturer's Code	V <sub>IL</sub>	0	0	1	0	0	0	0	0	20h
Device Code	V <sub>IH</sub>	0	0	1	1	1	1	0	1	3Dh



**Table 7. Read Mode DC Characteristics (1)**(T<sub>A</sub> = 0 to 70 °C or -40 to 85 °C; V<sub>CC</sub> = 3.3V ± 10%; V<sub>PP</sub> = V<sub>CC</sub>)

Symbol	Parameter	Test Condition	Min	Max	Unit
I <sub>LI</sub>	Input Leakage Current	0V ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>		±10	μA
I <sub>LO</sub>	Output Leakage Current	0V ≤ V <sub>OUT</sub> ≤ V <sub>CC</sub>		±10	μA
I <sub>CC</sub>	Supply Current	$\bar{E} = V_{IL}, \bar{G} = V_{IL}, I_{OUT} = 0mA,$ f = 5MHz, V <sub>CC</sub> ≤ 3.6V		10	mA
I <sub>CC1</sub>	Supply Current (Standby) TTL	$\bar{E} = V_{IH}$		1	mA
I <sub>CC2</sub>	Supply Current (Standby) CMOS	$\bar{E} > V_{CC} - 0.2V, V_{CC} \leq 3.6V$		10	μA
I <sub>PP</sub>	Program Current	V <sub>PP</sub> = V <sub>CC</sub>		10	μA
V <sub>IL</sub>	Input Low Voltage		-0.3	0.8	V
V <sub>IH</sub> (2)	Input High Voltage		2	V <sub>CC</sub> + 1	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1mA		0.4	V
V <sub>OH</sub>	Output High Voltage TTL	I <sub>OH</sub> = -400μA	2.4		V
V <sub>OH</sub>	Output High Voltage CMOS	I <sub>OH</sub> = -100μA	V <sub>CC</sub> - 0.7V		V

Note: 1. V<sub>CC</sub> must be applied simultaneously with or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.2. Maximum DC voltage on Output is V<sub>CC</sub> + 0.5V.**Table 8A. Read Mode AC Characteristics (1)**(T<sub>A</sub> = 0 to 70 °C or -40 to 85 °C; V<sub>CC</sub> = 3.3V ± 10%; V<sub>PP</sub> = V<sub>CC</sub>)

Symbol	Alt	Parameter	Test Condition	M27V512				Unit
				-100 (3)		-120		
				Min	Max	Min	Max	
t <sub>AVQV</sub>	t <sub>ACC</sub>	Address Valid to Output Valid	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$		100		120	ns
t <sub>ELQV</sub>	t <sub>CE</sub>	Chip Enable Low to Output Valid	$\bar{G} = V_{IL}$		100		120	ns
t <sub>GLQV</sub>	t <sub>OE</sub>	Output Enable Low to Output Valid	$\bar{E} = V_{IL}$		45		45	ns
t <sub>EHQZ</sub> (2)	t <sub>DF</sub>	Chip Enable High to Output Hi-Z	$\bar{G} = V_{IL}$	0	30	0	35	ns
t <sub>GHQZ</sub> (2)	t <sub>DF</sub>	Output Enable High to Output Hi-Z	$\bar{E} = V_{IL}$	0	30	0	35	ns
t <sub>AXQX</sub>	t <sub>OH</sub>	Address Transition to Output Transition	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$	0		0		ns

Note: 1. V<sub>CC</sub> must be applied simultaneously with or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.

2. Sampled only, not 100% tested.

3. Speed obtained with High Speed AC measurement conditions.

**Two Line Output Control**

Because EPROMs are usually used in larger memory arrays, the product features a 2 line control function which accommodates the use of multiple memory connection. The two line control function allows:

- the lowest possible memory power dissipation,
- complete assurance that output bus contention will not occur.

For the most efficient use of these two control lines,  $\bar{E}$  should be decoded and used as the primary device selecting function, while  $\bar{G}$  should be made a common connection to all devices in the array and connected to the  $\overline{READ}$  line from the system control bus. This ensures that all deselected memory devices are in their low power standby mode and that the output pins are only active when data is required from a particular memory device.

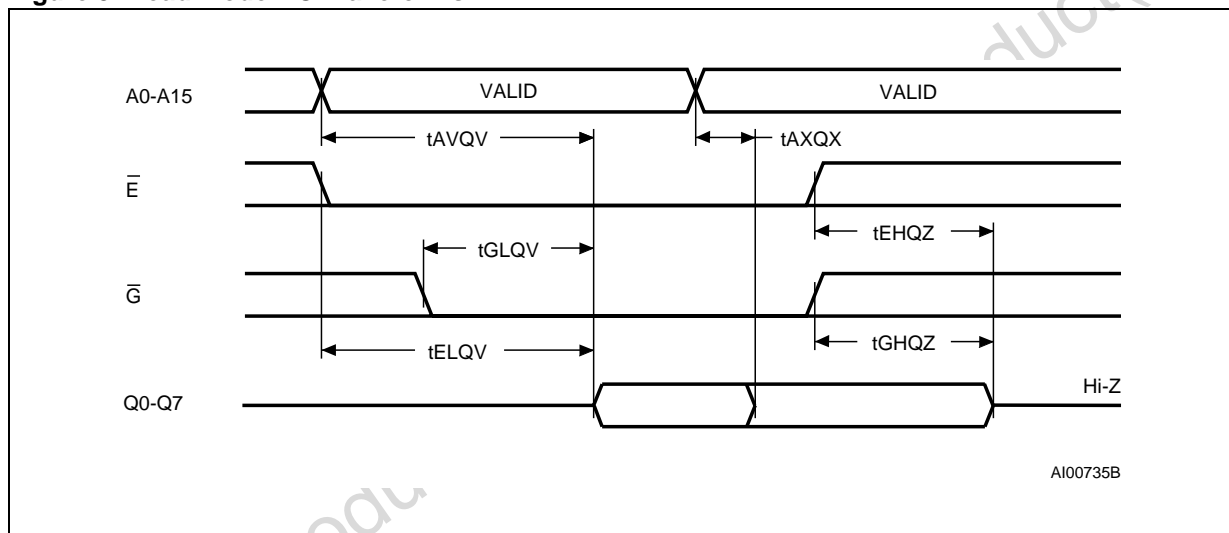
**Table 8B. Read Mode AC Characteristics <sup>(1)</sup>**

( $T_A = 0$  to  $70$  °C or  $-40$  to  $85$  °C;  $V_{CC} = 3.3V \pm 10\%$ ;  $V_{PP} = V_{CC}$ )

Symbol	Alt	Parameter	Test Condition	M27V512				Unit
				-150		-200		
				Min	Max	Min	Max	
$t_{AVQV}$	$t_{ACC}$	Address Valid to Output Valid	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$		150		200	ns
$t_{ELQV}$	$t_{CE}$	Chip Enable Low to Output Valid	$\bar{G} = V_{IL}$		150		200	ns
$t_{GLQV}$	$t_{OE}$	Output Enable Low to Output Valid	$\bar{E} = V_{IL}$		50		60	ns
$t_{EHQZ}^{(2)}$	$t_{DF}$	Chip Enable High to Output Hi-Z	$\bar{G} = V_{IL}$	0	40	0	50	ns
$t_{GHQZ}^{(2)}$	$t_{DF}$	Output Enable High to Output Hi-Z	$\bar{E} = V_{IL}$	0	40	0	50	ns
$t_{AXQX}$	$t_{OH}$	Address Transition to Output Transition	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$	0		0		ns

Note: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .  
 2. Sampled only, not 100% tested.

**Figure 5. Read Mode AC Waveforms**



**System Considerations**

The power switching characteristics of Advanced CMOS EPROMs require careful decoupling of the devices. The supply current,  $I_{CC}$ , has three segments that are of interest to the system designer: the standby current level, the active current level, and transient current peaks that are produced by the falling and rising edges of  $\bar{E}$ . The magnitude of the transient current peaks is dependent on the capacitive and inductive loading of the device at the output. The associated transient voltage peaks can be suppressed by complying with the two line

output control and by properly selected decoupling capacitors. It is recommended that a  $0.1\mu F$  ceramic capacitor be used on every device between  $V_{CC}$  and  $V_{SS}$ . This should be a high frequency capacitor of low inherent inductance and should be placed as close to the device as possible. In addition, a  $4.7\mu F$  bulk electrolytic capacitor should be used between  $V_{CC}$  and  $V_{SS}$  for every eight devices. The bulk capacitor should be located near the power supply connection point. The purpose of the bulk capacitor is to overcome the voltage drop caused by the inductive effects of PCB traces.

**Table 9. Programming Mode DC Characteristics (1)**  
( $T_A = 25\text{ }^\circ\text{C}$ ;  $V_{CC} = 6.25\text{V} \pm 0.25\text{V}$ ;  $V_{PP} = 12.75\text{V} \pm 0.25\text{V}$ )

Symbol	Parameter	Test Condition	Min	Max	Unit
$I_{LI}$	Input Leakage Current	$V_{IL} \leq V_{IN} \leq V_{IH}$		$\pm 10$	$\mu\text{A}$
$I_{CC}$	Supply Current			50	$\text{mA}$
$I_{PP}$	Program Current	$\bar{E} = V_{IL}$		50	$\text{mA}$
$V_{IL}$	Input Low Voltage		-0.3	0.8	$\text{V}$
$V_{IH}$	Input High Voltage		2	$V_{CC} + 0.5$	$\text{V}$
$V_{OL}$	Output Low Voltage	$I_{OL} = 2.1\text{mA}$		0.4	$\text{V}$
$V_{OH}$	Output High Voltage TTL	$I_{OH} = -1\text{mA}$	3.6		$\text{V}$
$V_{ID}$	A9 Voltage		11.5	12.5	$\text{V}$

Note: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .

**Table 10. MARGIN MODE AC Characteristics (1)**  
( $T_A = 25\text{ }^\circ\text{C}$ ;  $V_{CC} = 6.25\text{V} \pm 0.25\text{V}$ ;  $V_{PP} = 12.75\text{V} \pm 0.25\text{V}$ )

Symbol	Alt	Parameter	Test Condition	Min	Max	Unit
$t_{A9HVPH}$	$t_{AS9}$	$V_{A9}$ High to $V_{PP}$ High		2		$\mu\text{s}$
$t_{VPHEL}$	$t_{VPS}$	$V_{PP}$ High to Chip Enable Low		2		$\mu\text{s}$
$t_{A10HEH}$	$t_{AS10}$	$V_{A10}$ High to Chip Enable High (Set)		1		$\mu\text{s}$
$t_{A10LEH}$	$t_{AS10}$	$V_{A10}$ Low to Chip Enable High (Reset)		1		$\mu\text{s}$
$t_{EXA10X}$	$t_{AH10}$	Chip Enable Transition to $V_{A10}$ Transition		1		$\mu\text{s}$
$t_{EXVPX}$	$t_{VPH}$	Chip Enable Transition to $V_{PP}$ Transition		2		$\mu\text{s}$
$t_{VPXA9X}$	$t_{AH9}$	$V_{PP}$ Transition to $V_{A9}$ Transition		2		$\mu\text{s}$

Note: 1.  $V_{CC}$  must be applied simultaneously with or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .

### Programming

The M27V512 has been designed to be fully compatible with the M27C512 and has the same electronic signature. As a result the M27V512 can be programmed as the M27C512 on the same programming equipments applying 12.75V on  $V_{PP}$  and 6.25V on  $V_{CC}$  by the use of the same PRESTO IIB algorithm. When delivered (and after each erasure for UV EPROM), all bits of the M27V512 are in the '1' state. Data is introduced by selectively programming '0's into the desired bit locations. Although only '0's will be programmed, both '1's and '0's can be present in the data word. The only way to change a '0' to a '1' is by die exposure to ul-

traviolet light (UV EPROM). The M27V512 is in the programming mode when  $V_{PP}$  input is at 12.75V and  $\bar{E}$  is pulsed to  $V_{IL}$ . The data to be programmed is applied to 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL.  $V_{CC}$  is specified to be  $6.25\text{V} \pm 0.25\text{V}$ .

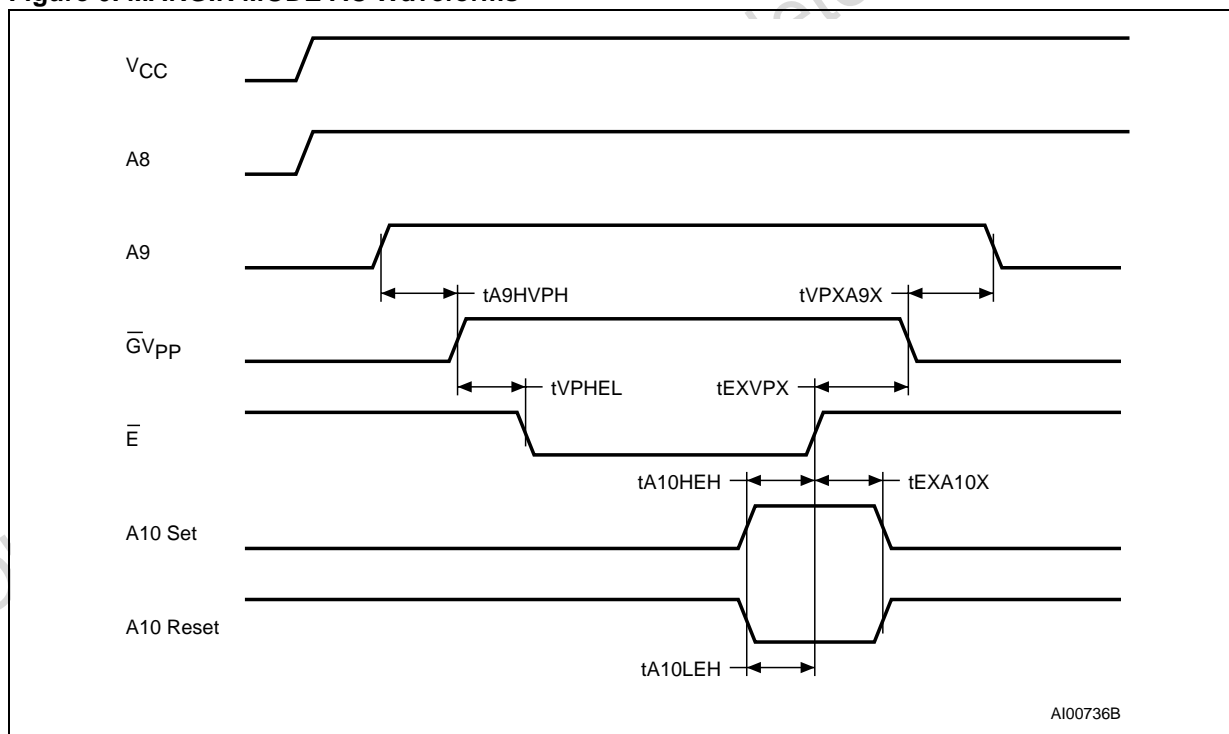
The M27V512 can use PRESTO IIB Programming Algorithm that drastically reduces the programming time (typically less than 6 seconds). Nevertheless to achieve compatibility with all programming equipments, PRESTO Programming Algorithm can be used as well.

**Table 11. Programming Mode AC Characteristics (1)**  
 (T<sub>A</sub> = 25 °C; V<sub>CC</sub> = 6.25V ± 0.25V; V<sub>PP</sub> = 12.75V ± 0.25V)

Symbol	Alt	Parameter	Test Condition	Min	Max	Unit
t <sub>AVEL</sub>	t <sub>AS</sub>	Address Valid to Chip Enable Low		2		μs
t <sub>QVEL</sub>	t <sub>DS</sub>	Input Valid to Chip Enable Low		2		μs
t <sub>VCHL</sub>	t <sub>VCS</sub>	V <sub>CC</sub> High to Chip Enable Low		2		μs
t <sub>VPHEL</sub>	t <sub>OES</sub>	V <sub>PP</sub> High to Chip Enable Low		2		μs
t <sub>VPLVPH</sub>	t <sub>PRT</sub>	V <sub>PP</sub> Rise Time		50		ns
t <sub>ELEH</sub>	t <sub>PW</sub>	Chip Enable Program Pulse Width (Initial)		95	105	μs
t <sub>EHQX</sub>	t <sub>DH</sub>	Chip Enable High to Input Transition		2		μs
t <sub>EHVPX</sub>	t <sub>OEH</sub>	Chip Enable High to V <sub>PP</sub> Transition		2		μs
t <sub>VPLEL</sub>	t <sub>VR</sub>	V <sub>PP</sub> Low to Chip Enable Low		2		μs
t <sub>ELQV</sub>	t <sub>DV</sub>	Chip Enable Low to Output Valid			1	μs
t <sub>EHQZ</sub> (2)	t <sub>DFP</sub>	Chip Enable High to Output Hi-Z		0	130	ns
t <sub>EHAX</sub>	t <sub>AH</sub>	Chip Enable High to Address Transition		0		ns

Note: 1. V<sub>CC</sub> must be applied simultaneously with or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.  
 2. Sampled only, not 100% tested.

**Figure 6. MARGIN MODE AC Waveforms**



Note: A8 High level = 5V; A9 High level = 12V.



Figure 7. Programming and Verify Modes AC Waveforms

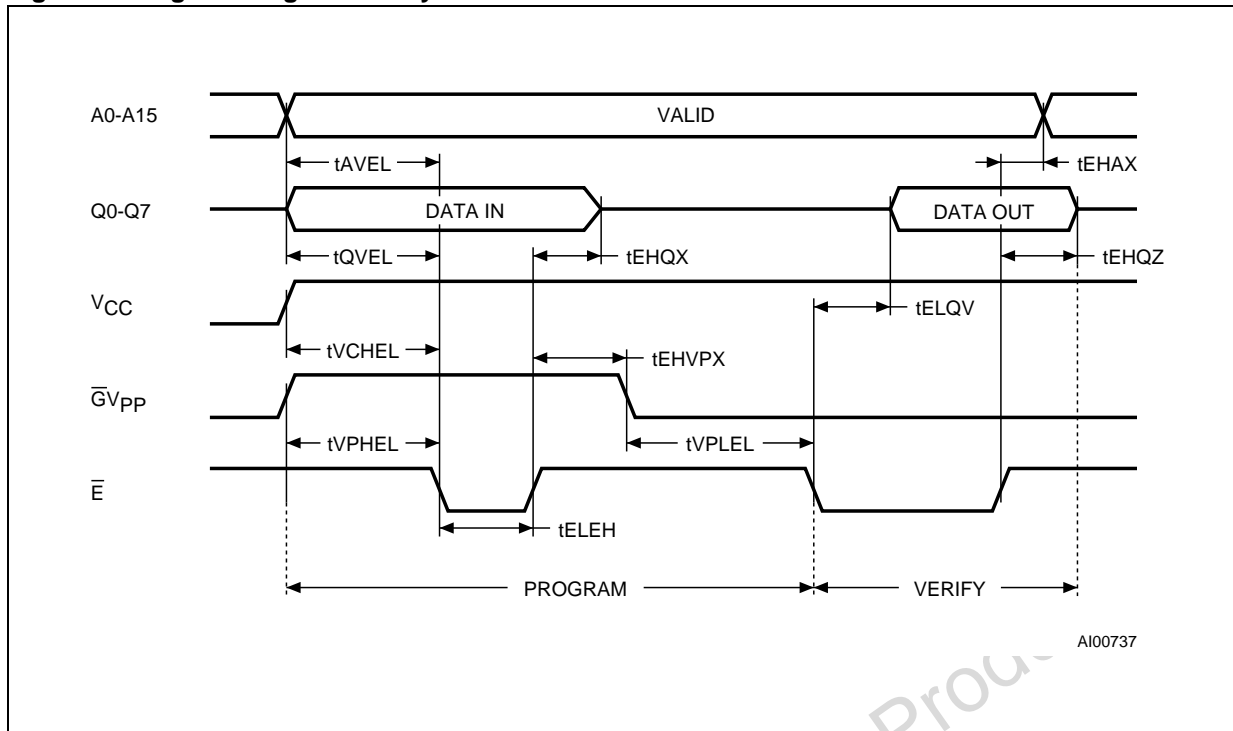
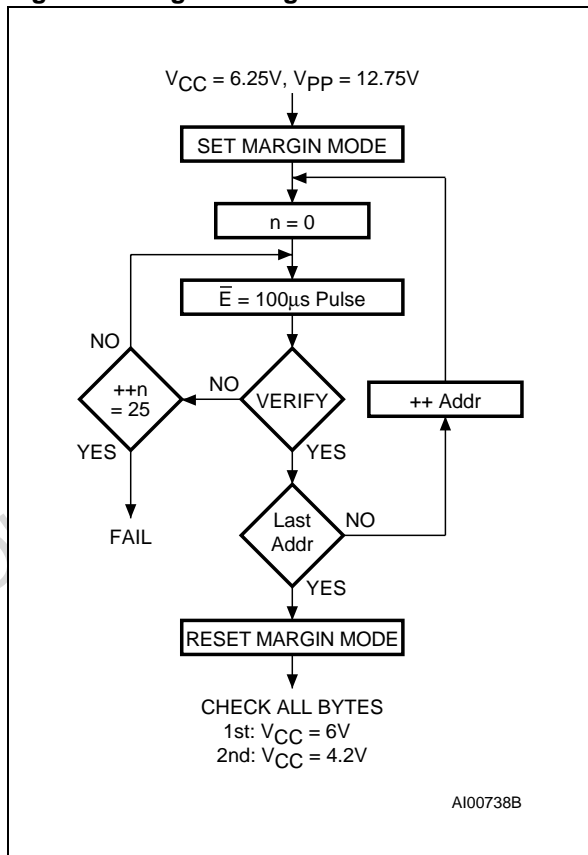


Figure 8. Programming Flowchart



**PRESTO IIB Programming Algorithm**

PRESTO IIB Programming Algorithm allows the whole array to be programmed with a guaranteed margin, in a typical time of 6.5 seconds. This can be achieved with STMicroelectronics M27V512 due to several design innovations described in the M27V512 datasheet to improve programming efficiency and to provide adequate margin for reliability. Before starting the programming the internal MARGIN MODE circuit is set in order to guarantee that each cell is programmed with enough margin. Then a sequence of 100µs program pulses are applied to each byte until a correct verify occurs. No overprogram pulses are applied since the verify in MARGIN MODE provides the necessary margin.

**Program Inhibit**

Programming of multiple M27V512s in parallel with different data is also easily accomplished. Except for E-bar, all like inputs including GVPP of the parallel M27V512 may be common. A TTL low level pulse applied to a M27V512's E-bar input, with VPP at 12.75V, will program that M27V512. A high level E-bar input inhibits the other M27V512s from being programmed.

**Program Verify**

A verify (read) should be performed on the programmed bits to determine that they were correctly programmed. The verify is accomplished with G-bar at VIL. Data should be verified with tELQV after the falling edge of E-bar.

### Electronic Signature

The Electronic Signature (ES) mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment to automatically match the device to be programmed with its corresponding programming algorithm. The ES mode is functional in the  $25^{\circ}\text{C} \pm 5^{\circ}\text{C}$  ambient temperature range that is required when programming the M27V512. To activate the ES mode, the programming equipment must force 11.5V to 12.5V on address line A9 of the M27V512. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from  $V_{IL}$  to  $V_{IH}$ . All other address lines must be held at  $V_{IL}$  during Electronic Signature mode.

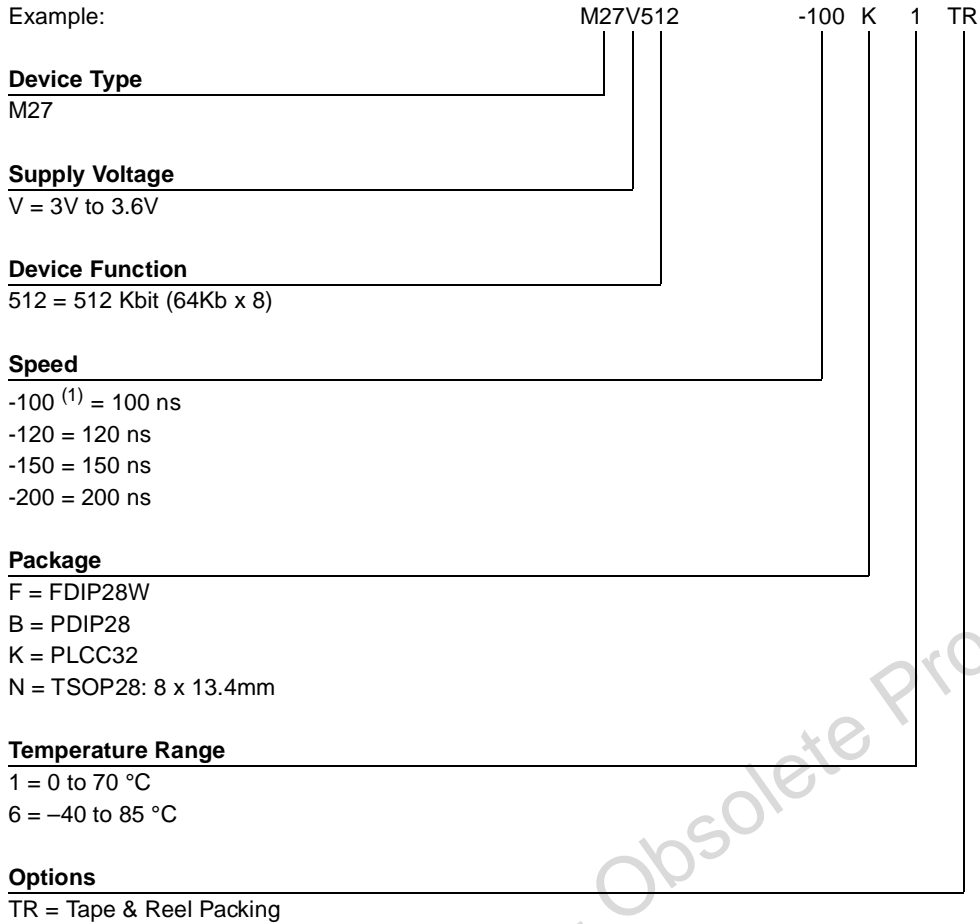
Byte 0 ( $A0 = V_{IL}$ ) represents the manufacturer code and byte 1 ( $A0 = V_{IH}$ ) the device identifier code. For the STMicroelectronics M27V512, these two identifier bytes are given in Table 4 and can be read-out on outputs Q7 to Q0. Note that the M27V512 and M27C512 have the same identifier bytes.

### ERASURE OPERATION (applies for UV EPROM)

The erasure characteristics of the M27V512 is such that erasure begins when the cells are exposed to light with wavelengths shorter than approximately 4000 Å. It should be noted that sunlight and some type of fluorescent lamps have wavelengths in the 3000-4000 Å range.

Research shows that constant exposure to room level fluorescent lighting could erase a typical M27V512 in about 3 years, while it would take approximately 1 week to cause erasure when exposed to direct sunlight. If the M27V512 is to be exposed to these types of lighting conditions for extended periods of time, it is suggested that opaque labels be put over the M27V512 window to prevent unintentional erasure. The recommended erasure procedure for the M27V512 is exposure to short wave ultraviolet light which has wavelength 2537 Å. The integrated dose (i.e. UV intensity x exposure time) for erasure should be a minimum of 15 W-sec/cm<sup>2</sup>. The erasure time with this dosage is approximately 15 to 20 minutes using an ultraviolet lamp with 12000µW/cm<sup>2</sup> power rating. The M27V512 should be placed within 2.5 cm (1 inch) of the lamp tubes during the erasure. Some lamps have a filter on their tubes which should be removed before erasure.

**Table 12. Ordering Information Scheme**



Note: 1. High Speed, see AC Characteristics section for further information.

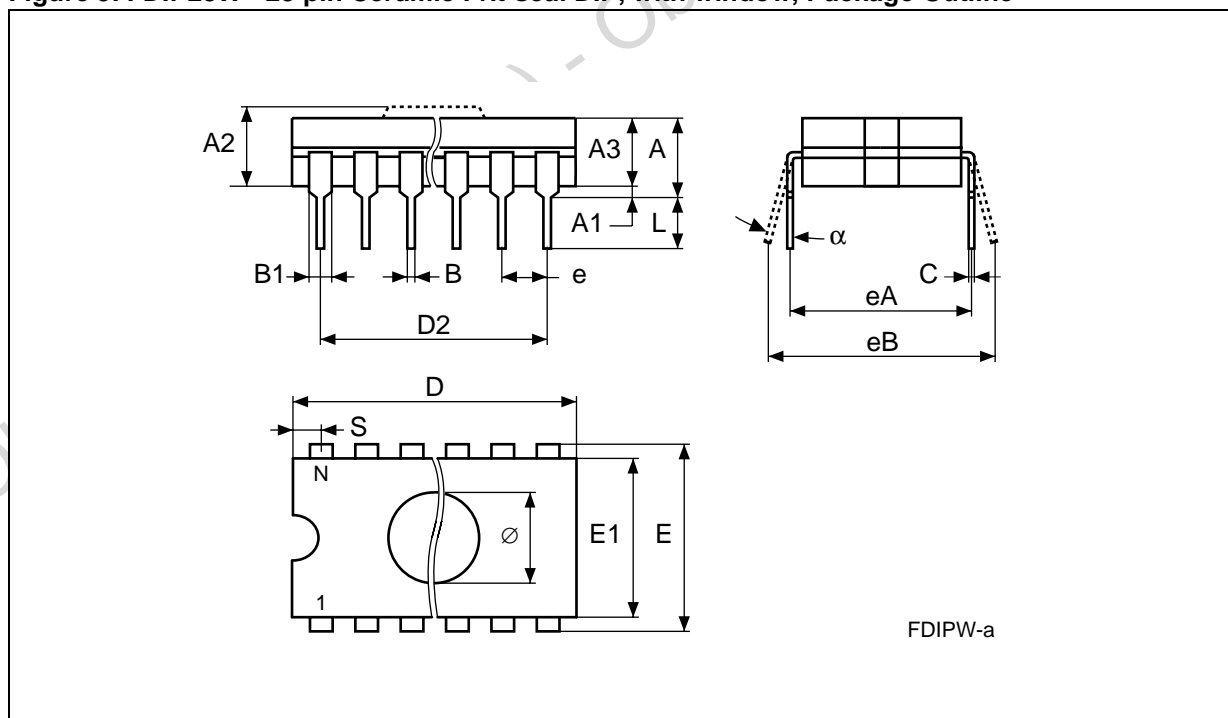
**M27V512 is replaced by the M27W512**

For a list of available options (Speed, Package, etc..) or for further information on any aspect of this device, please contact the STMicroelectronics Sales Office nearest to you.

Table 13. FDIP28W - 28 pin Ceramic Frit-seal DIP, with window, Package Mechanical Data

Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A			5.71			0.225
A1		0.50	1.78		0.020	0.070
A2		3.90	5.08		0.154	0.200
B		0.40	0.55		0.016	0.022
B1		1.17	1.42		0.046	0.056
C		0.22	0.31		0.009	0.012
D			38.10			1.500
E		15.40	15.80		0.606	0.622
E1		13.05	13.36		0.514	0.526
e1	2.54	–	–	0.100	–	–
e3	33.02	–	–	1.300	–	–
eA		16.17	18.32		0.637	0.721
L		3.18	4.10		0.125	0.161
S		1.52	2.49		0.060	0.098
∅	7.11	–	–	0.280	–	–
α		4°	15°		4°	15°
N		28			28	

Figure 9. FDIP28W - 28 pin Ceramic Frit-seal DIP, with window, Package Outline

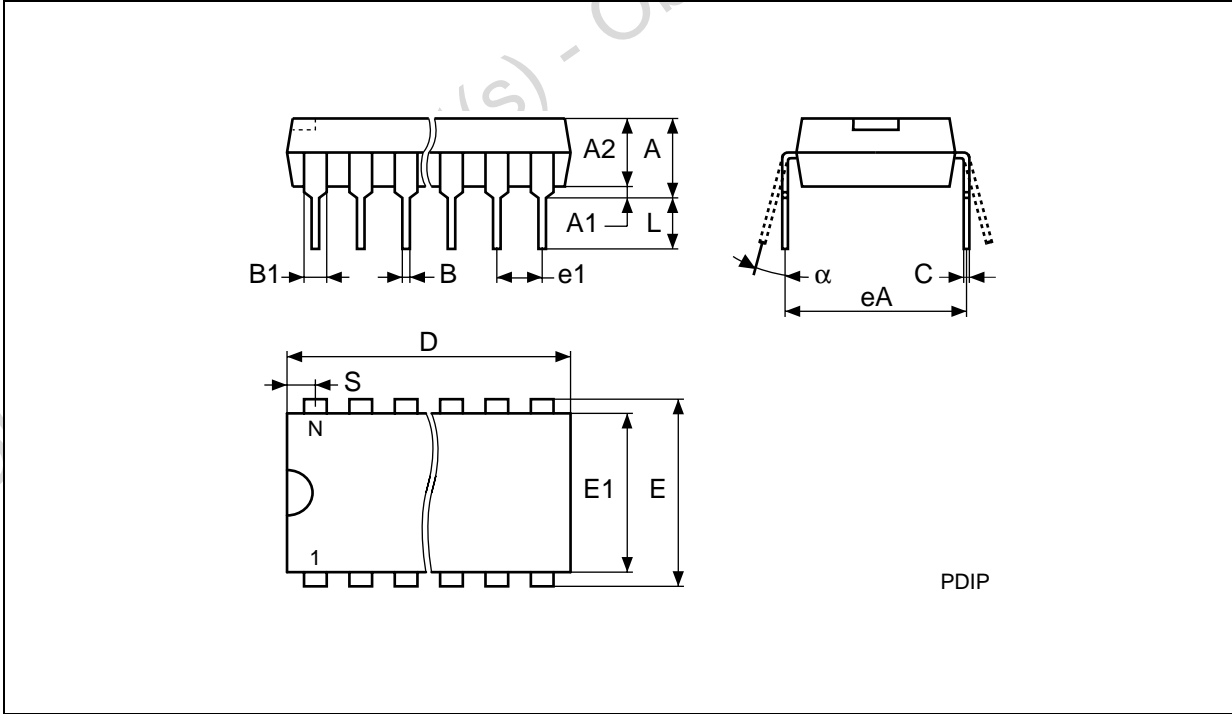


Drawing is not to scale.

Table 14. PDIP28 - 28 pin Plastic DIP, 600 mils width, Package Mechanical Data

Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A		–	5.08		–	0.200
A1		0.38	–		0.015	–
A2		3.56	4.06		0.140	0.160
B		0.38	0.51		0.015	0.020
B1	1.52	–	–	0.060	–	–
C		0.20	0.30		0.008	0.012
D		36.83	37.34		1.450	1.470
D2	33.02	–	–	1.300	–	–
E	15.24	–	–	0.600	–	–
E1		13.59	13.84		0.535	0.545
e1	2.54	–	–	0.100	–	–
eA	14.99	–	–	0.590	–	–
eB		15.24	17.78		0.600	0.700
L		3.18	3.43		0.125	0.135
S		1.78	2.08		0.070	0.082
$\alpha$		0°	10°		0°	10°
N		28			28	

Figure 10. PDIP28 - 28 pin Plastic DIP, 600 mils width, Package Outline

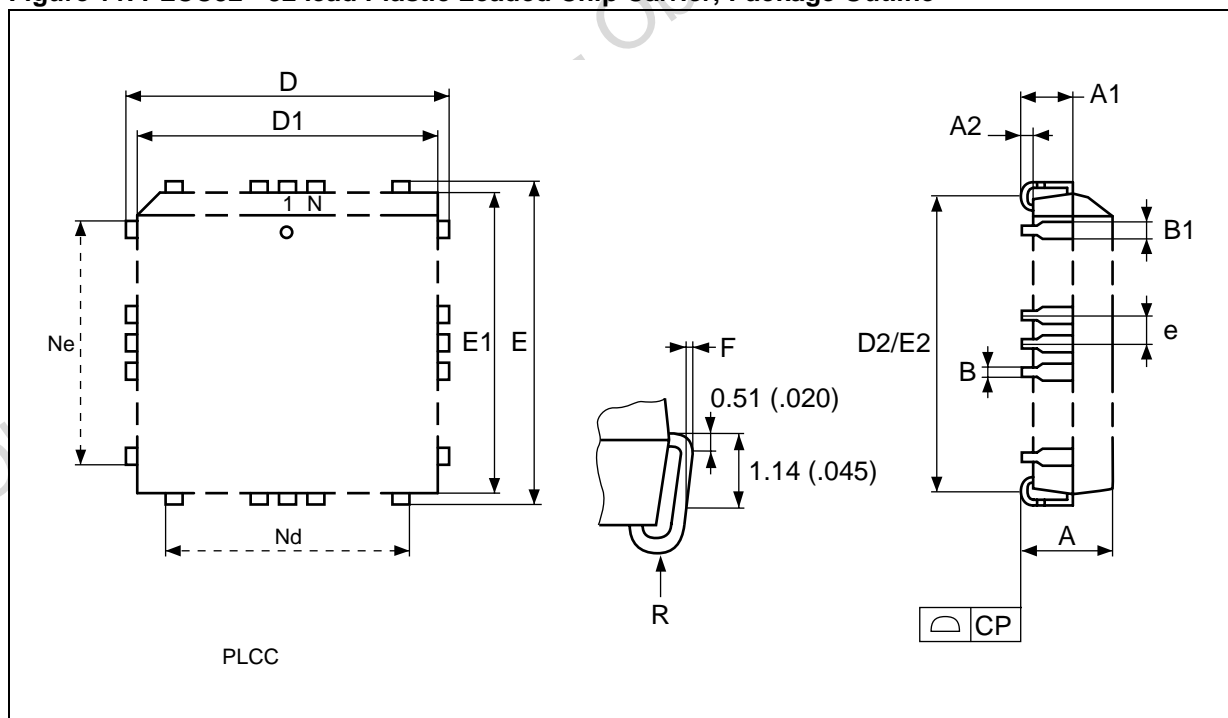


Drawing is not to scale.

Table 15. PLCC32 - 32 lead Plastic Leaded Chip Carrier, Package Mechanical Data

Symb	mm			inches			
	Typ	Min	Max	Typ	Min	Max	
A		2.54	3.56		0.100	0.140	
A1		1.52	2.41		0.060	0.095	
A2		0.38	–		0.015	–	
B		0.33	0.53		0.013	0.021	
B1		0.66	0.81		0.026	0.032	
D		12.32	12.57		0.485	0.495	
D1		11.35	11.56		0.447	0.455	
D2		9.91	10.92		0.390	0.430	
E		14.86	15.11		0.585	0.595	
E1		13.89	14.10		0.547	0.555	
E2		12.45	13.46		0.490	0.530	
e	1.27	–	–	0.050	–	–	
F		0.00	0.25		0.000	0.010	
R	0.89	–	–	0.035	–	–	
N		32			32		
Nd		7			7		
Ne	9			9			
CP			0.10			0.004	

Figure 11. PLCC32 - 32 lead Plastic Leaded Chip Carrier, Package Outline

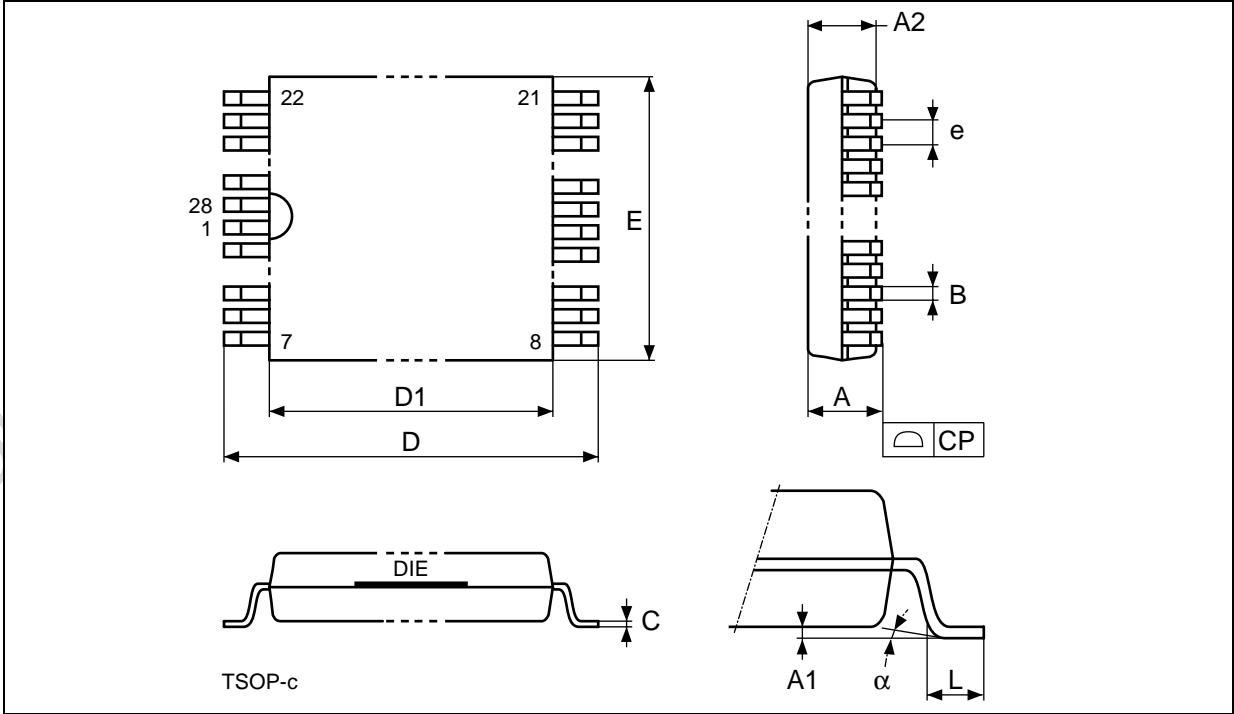


Drawing is not to scale.

Table 16. TSOP28 - 28 lead Plastic Thin Small Outline, 8 x 13.4 mm, Package Mechanical Data

Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A			1.25			0.049
A1			0.20			0.008
A2		0.95	1.15		0.037	0.045
B		0.17	0.27		0.007	0.011
C		0.10	0.21		0.004	0.008
D		13.20	13.60		0.520	0.535
D1		11.70	11.90		0.461	0.469
E		7.90	8.10		0.311	0.319
e	0.55	-	-	0.022	-	-
L		0.50	0.70		0.020	0.028
$\alpha$		0°	5°		0°	5°
N	28			28		
CP			0.10			0.004

Figure 12. TSOP28 - 28 lead Plastic Thin Small Outline, 8 x 13.4 mm, Package Outline



Drawing is not to scale

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